

HEXFET® POWER MOSFET

JANTX2N6845 JANTXV2N6845

[REF:MIL-PRF-19500/563]

[GENERIC:IRFF9120]

-100 Volt, 0.60Ω HEXFET

HEXFET technology is the key to International Rectifier's advanced line of power MOSFET transistors. The efficient geometry achieves very low onstate resistance combined with high transconductance. HEXFET transistors also feature all of the well-establish advantages of MOSFETs, such as voltage control, very fast switching, ease of paralleling and electrical parameter temperature stability. They are well-suited for applications such as switching power supplies, motor controls, inverters, choppers, audio amplifiers, and high energy pulse circuits, and virtually any application where high reliability is required.

Product Summary

Part Number	BVDSS	RDS(on)	lD
JANTX2N6845	-100V	0.60Ω	-4.0A
JANTXV2N6845	-1007	0.002	- 4 .0A

Features:

- Avalanche Energy Rating
- Dynamic dv/dt Rating
- Simple Drive Requirements
- Ease of Paralleling
- Hermetically Sealed

Absolute Maximum Ratings

	Parameter	JANTX2N6845, JANTXV2N6845	Units
ID @ VGS = -10V, TC = 25°C	Continuous Drain Current	-4.0	
$I_D @ V_{GS} = -10V, T_C = 100^{\circ}C$	Continuous Drain Current	-2.6	Α
IDM	Pulsed Drain Current ①	-16	
P _D @ T _C = 25°C	Max. Power Dissipation	20	W
	Linear Derating Factor	0.16	W/K ®
VGS	Gate-to-Source Voltage	±20	V
dv/dt	Peak Diode Recovery dv/dt ®	-5.0	V/ns
TJ	Operating Junction	-55 to 150	
TSTG	Storage Temperature Range		
	Lead Temperature	300 (0.063 in. (1.6mm) from	00
		case for 10.5 seconds)	∞
	Weight	0.98 (typical)	g

Electrical Characteristics @ Tj = 25°C (Unless Otherwise Specified)

	Parameter	Min.	Тур.	Max.	Units	Test Conditions	
BVDSS	Drain-to-Source Breakdown Voltage	-100	_	_	V	$V_{GS} = 0V, I_{D} = -1.0 \text{ mA}$	
ΔBVDSS/ΔTJ	Temperature Coefficient of Breakdown Voltage	_	-0.10	_	V/°C	Reference to 25°C, I _D = -1.0 mA	
RDS(on)	Static Drain-to-Source		_	0.60		VGS = -10V, ID = -2.6A ⁽⁴⁾	
	On-State Resistance	_	_	0.69	Ω	VGS = -10V, ID = -4.0A	
VGS(th)	Gate Threshold Voltage	-2.0	_	-4.0	V	$VDS = VGS$, $ID = -250\mu A$	
gfs	Forward Transconductance	1.25	_	_	S (U)	VDS > -15V, IDS = -2.6A @	
IDSS	Zero Gate Voltage Drain Current	_	_	-25	_	$V_{DS} = 0.8 \times Max Rating, V_{GS} = 0V$	
		_	_	-250	μΑ	V _{DS} = 0.8 x Max Rating	
						VGS = 0V, TJ = 125°C	
IGSS	Gate-to-Source Leakage Forward		_	-100	nA	VGS = -20V	
IGSS	Gate-to-Source Leakage Reverse		_	100	''^	VGS = 20V	
Qg	Total Gate Charge	4.3	_	16.3		VGS = -10V, ID = -4.0A	
Qgs	Gate-to-Source Charge	1.3	_	4.7	nC	VDS = Max. Rating x 0.5	
Qgd	Gate-to-Drain ("Miller") Charge	1.0	_	9.0		see figures 6 and 13	
td(on)	Turn-On Delay Time	_	_	60		VDD = -50V, ID = -4.0A,	
tr	Rise Time	_	_	100	ns	$RG = 7.5\Omega$, $VGS = -10V$	
td(off)	Turn-Off Delay Time	_	_	50	115		
tf	Fall Time	_	_	70		see figure 10	
LD	Internal Drain Inductance	_	5.0	_	nH	Measured from the drain lead, 6mm (0.25 in.) from package to center of die. Modified MOSFET symbol showing the internal inductances.	
LS	Internal Source Inductance	_	15	_	1 1111	Measured from the source lead, 6mm (0.25 in.) from package to source bonding pad.	
Ciss	Input Capacitance		380	_		VGS = 0V, VDS = -25V	
Coss	Output Capacitance		170		pF	f = 1.0 MHz	
C _{rss}	Reverse Transfer Capacitance	_	45	_		see figure 5	

Source-Drain Diode Ratings and Characteristics

	Parameter		Min.	Тур.	Max.	Units	Test Conditions
Is	Continuous Source Current (Body Diode)		_	_	-4.0	Α	Modified MOSFET symbol showing the
ISM	SM Pulse Source Current (Body Diode) ①		_	_	-16	,	integral reverse p-n junction rectifier.
VSD	Diode Forward Voltage		_	_	-4.8	V	Tj = 25°C, IS = -4.0A, VGS = 0V 4
t _{rr}	Reverse Recovery Time		_	_	200	ns	$T_j = 25^{\circ}C$, $I_F = -4.0A$, $di/dt \le -100A/\mu s$
QRR	R Reverse Recovery Charge		_	_	3.1	μC	V _{DD} ≤ -50V ④
ton	Forward Turn-On Time	Intrinsic turn-on time is negligible. Turn-on speed is substantially controlled by $L_S + L_D$.					

Thermal Resistance

	Parameter	Min.	Тур.	Max.	Units	Test Conditions
R _{th} JC	Junction-to-Case	_	_	6.25		
R _{th} JA	Junction-to-Ambient	_	_	175	K/W	Typical socket mount

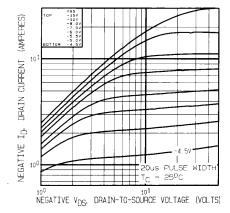


Fig. 1 — Typical Output Characteristics $T_C = 25^{\circ}C$

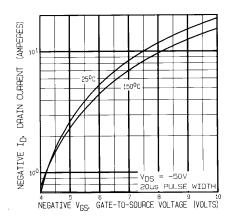


Fig. 3 — Typical Transfer Characteristics

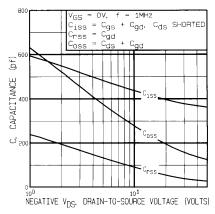


Fig. 5 — Typical Capacitance Vs. Drain-to-Source Voltage

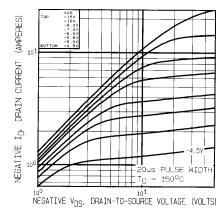


Fig. 2 — Typical Output Characteristics $T_C = 150$ °C

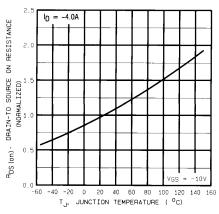


Fig. 4 — Normalized On-Resistance Vs.Temperature

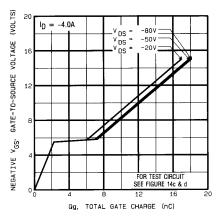


Fig. 6 — Typical Gate Charge Vs. Gate-to-Source Voltage

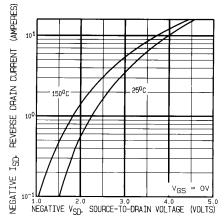


Fig. 7 — Typical Source-to-Drain Diode Forward Voltage

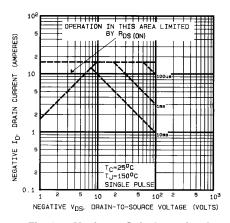


Fig. 8 — Maximum Safe Operating Area

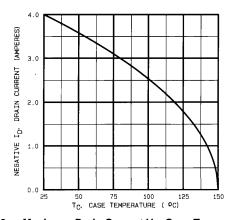


Fig. 9 — Maximum Drain Current Vs. Case Temperature

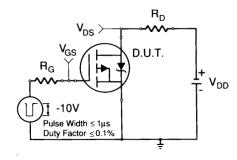


Fig. 10a — Switching Time Test Circuit

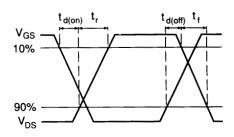


Fig. 10b — Switching Time Waveforms

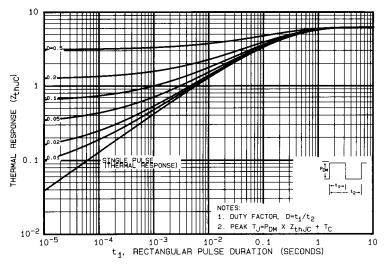


Fig. 11 — Maximum Effective Transient Thermal Impedance, Junction-to-Case Vs. Pulse Duration

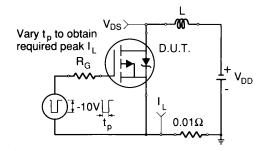


Fig. 12a — Unclamped Inductive Test Circuit

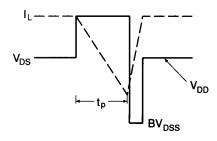


Fig. 12b — Unclamped Inductive Waveforms

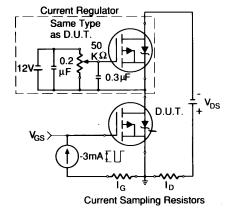


Fig. 13a — Gate Charge Test Circuit

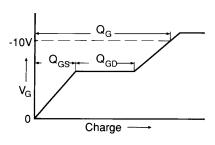
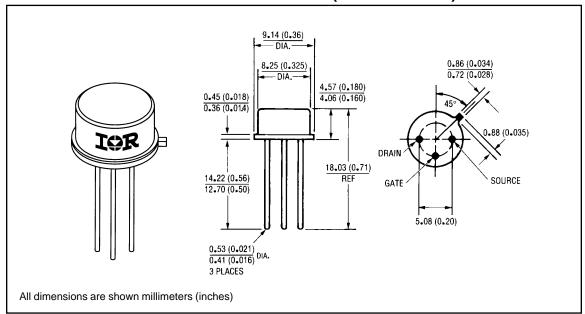


Fig. 13b — Basic Gate Charge Waveform

- Repetitive Rating; Pulse width limited by maximum junction temperature. (see figure 11)
- ② @ VDD = -25V, Starting TJ = 25°C, EAS = $[0.5 * L * (I_L^2) * [BVDSS/(BVDSS-VDD)]$ Peak IL = -4.0A, VGS = -10V, 25 ≤ RG ≤ 200 Ω
- ③ ISD ≤ -4.0A, di/dt ≤ -110A/ μ s, VDD ≤ BVDSS, TJ ≤ 150°C
- ⓐ Pulse width ≤ 300 μ s; Duty Cycle ≤ 2%
- ⑤ K/W = °C/W W/K = W/°C

Case Outline and Dimensions — TO-205AF (Modified TO-39)



International TOR Rectifier

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